



# Reliability Data Report

## Product Family R555

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LT8490

# Reliability Data Report

## Report Number: R555

Report generated on: Fri May 23 08:38:02 PDT 2014

### OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) <sup>1</sup>	No. of FAILURES <sub>2,3</sub>
QFN/DFN	77	1304	1304	0	0
Totals	77	-	-	0	0

### PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	152	1236	1236	25	0
Totals	152	-	-	25	0

### TEMP CYCLE FROM -65 TO 150 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	153	1236	1236	153	0
Totals	153	-	-	153	0

### THERMAL SHOCK FROM -65 TO 150 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	154	1236	1236	154	0
Totals	154	-	-	154	0

### HIGH TEMPERATURE BAKE AT 175 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	154	1236	1236	154	0
Totals	154	-	-	154	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level = FITS

(3) Mean Time Between Failure in Years = 0

Note: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning